

Search Notes

Application/Control No.

10/531,050

Examiner

David Mis

Applicant(s)/Patent under
Reexamination

HIRANO ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
332	103-105	9/28/2006	DM
331	16		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR